Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
09/580,808	SEZAN ET AL.
Examiner	Art Unit
Annan Q. Shang	2617

SEARCHED				
Class	Subclass	Date	Examiner	
725	87-94,100- 1-3	10/27/2005	A.S	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH	TES STRATEGY)
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